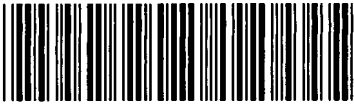


**Search Notes**

Application/Control No.

10/743,931

Examiner

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Applicant(s)/Patent under  
Reexamination

JUNG ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	224	6/20/2007	DB
709	223	6/20/2007	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/20/2007	DB
Double Patenting search	6/20/2007	DB